PCN Number: 202				210413000.1 P			CN Date:		Apr 14, 2021
Title: Qualification of new Fab site (MIHO8) using qualified Process Technology, D Datasheet update and additional Assembly BOM options for select devices									
Customer Contact:			PC	<u>N Manager</u>		Dep	ot:		Quality Services
Proposed 1 st Ship Date:						Estimated Sample Availability:		nple	Date provided at sample request.
Change Type:									
Assem	bly Site		Assembly Process			\boxtimes	Assembly Materials		
Design			Electrical Specification				Mechanical Specification		
Test Site			Packing/Shipping/Labeling				Test Process		Process
Wafer	Bump Site	Wafer Bump Mat			rial			Wafe	r Bump Process
🛛 Wafer	Fab Site			Wafer Fab Materia	ıls		\boxtimes	Wafe	r Fab Process
			Part number change						
				DCN Data					

PCN Details

Description of Change:

Texas Instruments is pleased to announce the qualification of a new fab & process technology (MIHO8, 3370A07SX3) and Assembly BOM options for selected devices as listed below in the product affected section.

	Current Fa	b Site	New Fab Site			
Fab Site	e Process Wafer Diameter		Fab Site	Process	Wafer Diameter	
DL-LIN	50C40	200 mm	MIHO8	3370A07SX3	200 mm	

The die was also changed as a result of the process change.

The datasheets will be changing as a result of the above mentioned changes as shown below:

Device Family	Change From:	Change To:
TL16C550C	SLLS177H	SLLS177I

The product datasheet(s) is updated as seen in the change revision history below:

Texas Instruments	TL16C550C SLLS177I – MARCH 1994 – REVISED MARCH 2021
Changes from Revision H (January 2006) to Revision I (March 2021)	Page
Updated the data sheet format	1
Added the Pin Configuration and Functions section	
Added the Thermal Information table.	

These changes may be viewed at the datasheet link provided: http://www.ti.com/product/TL16C550C

Construction differences are noted below:

Group 1 MIHO8/Process migration, Datasheet changes, BOM comparison:

	PHI (Current)	PHI (New)
Mount Compound	4042504	4211470
Mold Compound	4207207	4222198

Qual details are provided in the Qual Data Section.

Reas	son for Change:					
Thes	e changes are part		, ,	transition products f		-
millimeter factories to newer, more efficient manufacturing processes and technologies,						
underscoring our commitment to product longevity and supply continuity. Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):						
			, FIC, FUNCTION, C		y (positive	e / llegative).
None	-					
Antio	cipated impact o		rial Declaration			
	No Impact to the Material			ations or Product Con		
	Declaration			and will be available production release th	_	
				he <u>TI ECO website</u> .		
Char	nges to product i	dentifio	cation resulting	from this PCN:		
Fah	Site Informatio	nı				
	Chip Site		hip Site Origin Co (20L)	de Chip Site Cou (21L		Chip Site City
	DL-LIN		DLN	USA		Dallas
	MIHO8		MH8	JPN		Ibaraki
Curr Die		New Die Rev A		ct label)		
Curr Die Samp INS MADE 2DC:	ent Rev [2P] A ple product shippin TEXAS TRUMENTS IN: China 20: 1 /260C/UNLIM S 1:	ng label		ct label) (1P)PTAS256 (Q) 3000 (31T)LOT: (4W) SWR (1 (P) (2P) REV: A0 (20L) CSO: DME (2L) ASO: JCF	(D) 7133710 T) 28555 (V) 00 (211) CC	33317 0:USA
Curr Die Samp INS MADE 2DC: MSL OPT: ITEN	Rev [2P] A ple product shippin TEXAS TRUMENTS IN: China 20: 1 /260C/UNLIM So 1 /260C/UNLIM So 1 /260C/UNLIM So 1 /260C/UNLIM So 1 / 260C/UNLIM So 1 / 260C/UNLIM <tr< td=""><td>Die Rev A ng label Pe A 4/14/17 73 1168</td><td>(not actual produc</td><td>(1P) PTAS256 (Q) 3000 (31T) LOT: (4W) SWR (1 (P) (2P) REV: A0 (20L) CSO: DMR (22L) ASO: JCF</td><td>(D) 7133710 T) 28555 (V) 00 (21L) CC (23L) AC</td><td>33317 0:USA 0: CHN</td></tr<>	Die Rev A ng label Pe A 4/14/17 73 1168	(not actual produc	(1P) PTAS256 (Q) 3000 (31T) LOT: (4W) SWR (1 (P) (2P) REV: A0 (20L) CSO: DMR (22L) ASO: JCF	(D) 7133710 T) 28555 (V) 00 (21L) CC (23L) AC	33317 0:USA 0: CHN
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- Tube devices are included in this notification to inform customers of the change to their replacement devices (tape and reel) and to have the opportunity to request samples, but will not be subject to this change and are included in EOL notice PDN# 20210413001.3

Qualification Report

Approve Date 30-Mar-2021

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: <u>TL16C550CIFNR</u>	QBS Product Reference: <u>TL16C550DIPT</u>	QBS Process Reference: <u>SN0406039PW</u>	QBS Package Reference: <u>COPCG-AMD/V-</u> <u>MPC/S2</u>	QBS Package Reference: <u>COPCG-AQQ/V-</u> <u>MPC/S2</u>	QBS Package Reference: <u>TPS76933DBVR</u>
AC	Autoclave 121C	96 Hours	-	-	3/231/0	2/154/0	1/77/0	3/231/0
CDM	ESD - CDM	1500 V	1/3/0	-	-	-	-	-
ED	Electrical Characterization	Per Data Sheet Parameters	-	Pass	-	-	-	-
ELFR	Early Life Failure Rate, 125C	48 Hours	-	-	3/2400/0	-	-	-
HAST	Biased HAST, 130C/85%RH	96 Hours	-	-	3/231/0	2/154/0	-	3/231/0
HBM	ESD - HBM	4000V	-	1/3/0	-	-	-	-
HTOL	Life Test, 125C	1000 Hours	-	-	1/77/0	-	-	-
HTOL	Life Test, 140C	649 Hours	-	-	2/154/0	-	-	-
HTOL	Life Test, 150C	300 Hours	-	-	-	-	-	3/230/0
HTOL	Life Test, 155C	240 Hours	-	1/77/0	-	-	-	-
HTSL	High Temp Storage Bake 170C	420 Hours	-	-	-	2/154/0	1/77/0	3/231/0
HTSL	High Temp Storage Bake 175C	500 Hours	-	-	1/45/0	-	-	-
LU	Latch Up	<u>(Per</u> JESD78)	-	1/5/0	-	-	-	-
SD	Surface Mount solderability	Pb Free	-	-	-	1/22/0	-	-
SD	Surface Mount solderability	Pb Free	-	-	-	1/22/0	-	-

	Туре	Test Name / Condition	Duration	Qual Device: <u>TL16C550CIFNR</u>	QBS Product Reference: <u>TL16C550DIPT</u>	QBS Process Reference: <u>SN0406039PW</u>	QBS Package Reference: <u>COPCG-AMD/V-</u> <u>MPC/S2</u>	QBS Package Reference: <u>COPCG-AQQ/V-</u> <u>MPC/S2</u>	QBS Package Reference: <u>TPS76933DBVR</u>
ſ	тс	Temperature Cycle, - 65/150C	500 Cycles	-	-	3/231/0	2/154/0	1/77/0	3/231/0
	TS	Thermal Shock - 65/150C	500 Cycles	-	1/77/0	3/231/0	-	-	-
	WBP	Bond Pull	Wires	1/76/0	-	-	-	-	-
	WBS	Ball Bond Shear	Wires	1/76/0	-	-	-	-	-

- QBS: Qual By Similarity

- Qual Device TL16C550CIFNR is qualified at LEVEL3-260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles
Quality and Environmental data is available at TI's external Web site: http://www.ti.com/
Green/Pb-free Status:
Qualified Pb-Free (SMT) and Green

Qualification Report

Approve Date 17-Nov-2020

	Data Displayed as. Number of lots / Total sample size / Total failed							
Туре	Test Name / Condition	Duration	Qual Device: <u>TL16C550CIP</u> <u>T</u>	QBS Product Reference: <u>TL16C550DIP</u> <u>I</u>	QBS Product Reference: <u>TL16C550DPT</u> <u>R</u>	QBS Process Reference: <u>SN0406039P</u> <u>W</u>	QBS Package Reference: <u>SN104950PA</u> <u>G</u>	QBS Package Reference: <u>TLV320AIC22P</u> <u>T</u>
AC	Autoclave 121C	96 Hours	-	-	1/77/0	3/231/0	-	3/231/0
CDM	ESD - CDM	1500V	-	1/3/0	-	-	-	-
ED	Electrical Characterizatio n	Per Data Sheet Parameter s	Pass	-	-	-	-	-
ELFR	Early Life Failure Rate, 125C	48 Hours	-	-	-	3/2400/0	-	-
HAS T	Biased HAST, 130C/85%RH	96 Hours	-	-	-	3/231/0	3/148/0	-
HBM	ESD - HBM	4000V	-	1/3/0	-	-	-	-
HTO L	Life Test, 125C	1000 Hours	-	-	-	1/77/0	3/119/0	-
HTO L	Life Test, 140C	480 Hours	-	-	-	2/154/0	-	-
HTO L	Life Test, 155C	240 Hours	-	1/77/0	-	-	-	-
HTSL	High Temp Storage Bake 170C	420 Hours	-	-	1/77/0	-	-	-
HTSL	High Temp Storage Bake 175C	500 Hours	-	-	-	1/45/0	-	-
HTSL	High Temp. Storage Bake, 150C	1000 Hours	-	-	-	-	-	3/231/0
LU	Latch Up	(Per JESD78)	-	1/5/0	-	-	-	-
тс	Temperature Cycle - 65/150C	500 Cycles	-	-	1/77/0	3/231/0	-	3/231/0
TS	Thermal Shock -65/150C	500 Cycles	-	-	1/77/0	3/231/0	-	3/231/0

Data Displayed as: Number of lots / Total sample size / Total failed

- QBS: Qual By Similarity

- Qual Device TL16C550CIPT is qualified at LEVEL2-260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours

- The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free (SMT) and Green

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